

CMOS Direct-Injection Divide-by-3 Injection-Locked Frequency Dividers

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Abstract—This paper proposes CMOS LC-tank divide-by-3 injection locked frequency dividers (ILFDs) fabricated in 0.18 μm and 90nm CMOS process and describes the circuit design, operation principle and measurement results of the ILFDs. The ILFDs use two injection series-MOSFETs across the LC resonator and a differential injection signal is applied to the gates of injection MOSFETs. The direct-injection divide-by-3 ILFDs are potential for radio-frequency application and can have wide locking range.

Keywords—LC-tank; divide-by-3 injection-locked frequency divider; direct-injection; locking range; CMOS.

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1 Introduction

Frequency dividers (FDs) are widely used for sub-blocks of phase locked loop (PLL) and carrier recovery blocks. A popular FD is the LC resonator based injection-locked frequency divider (ILFD) because the operating frequency can be very high and the divider consumes low power. They are free-running oscillators which lock in phase and frequency to an injected input signal. When the incident frequency is a harmonic of the oscillation frequency, frequency division is performed. The even-modulus ILFDs include divide-by-2/4 and the odd-modulus ILFDs include divide-by-3 circuits. Figure 1 shows the series-injection divide-by-3 ILFD [1, 2]. Figure 2 shows the parallel-injection divide-by-3 ILFD [3]. Figure 3 shows the direct-injection divide-by-3 ILFD [4]. The direct injection method can be used for higher frequency operation than the tail injection method. However, the

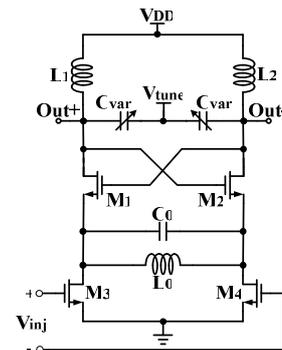


Fig. 1. Schematic of the series-injection divide-by-3 ILFD.

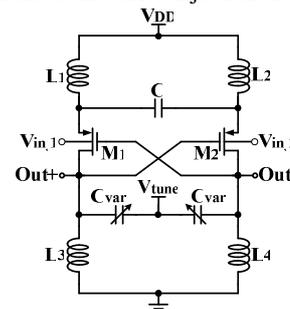


Fig. 2. Schematic of the parallel-injection divide-by-3 ILFD [3].

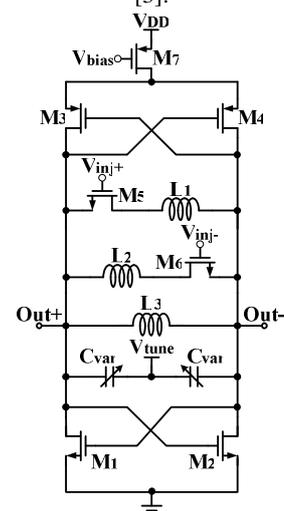


Fig. 3. Schematic of the direct-injection ILFD [4].

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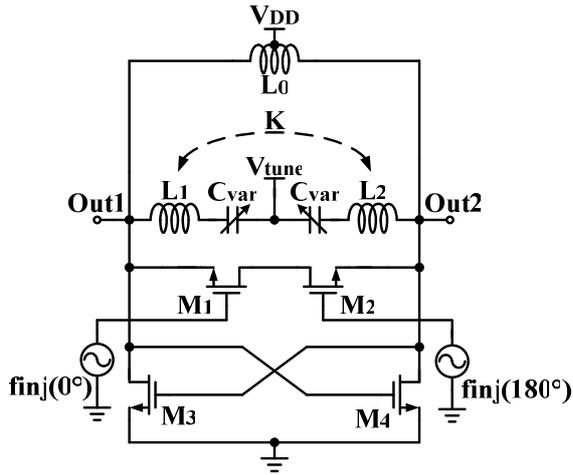


Fig. 4. Schematic of the studied direct-injection divide-by-3 injection-locked frequency divider.

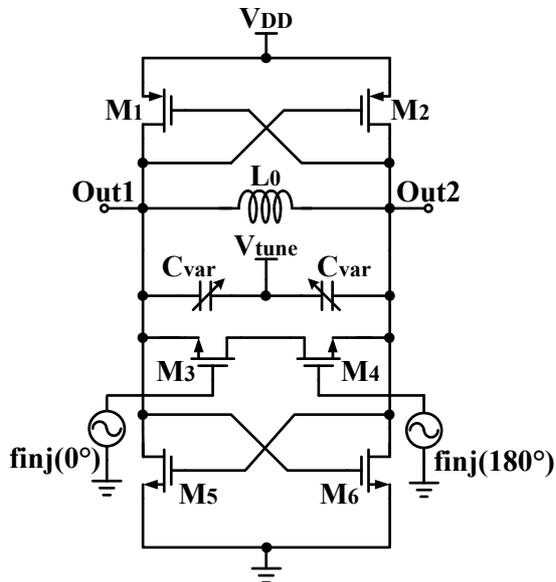


Fig. 5. Schematic of the direct-injection ILFD.

tail injection method uses stacked MOSFETs and is not a good option for low-voltage application as compared with the direct injection method.

The direct-injection method shown in Fig. 3 uses two inductors increase the die area and product cost. This paper proposed new direct-injection divide-by 3 ILFD for small die area. The organization of the paper is as follows. Section II gives a description of the circuit design and operation principle of the circuit, and then the measurement results are presented in Section III.

2 Circuit Design

The circuit diagrams of the studied divide-by-3 ILFD circuits are shown in Fig. 4 and 5. In Fig. 4, The ILFD circuit is a cross-coupled VCO with two injection MOSFETs, a pair of varactors C_{var} is used for frequency tuning, and it forms the resonator with the inductors ($L_0 \sim L_2$). The voltage V_{tune} is used to

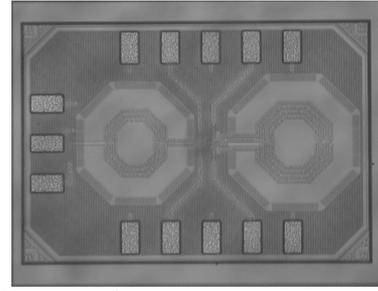


Fig. 6(a). Chip photo of the divide-by-3 ILFD.

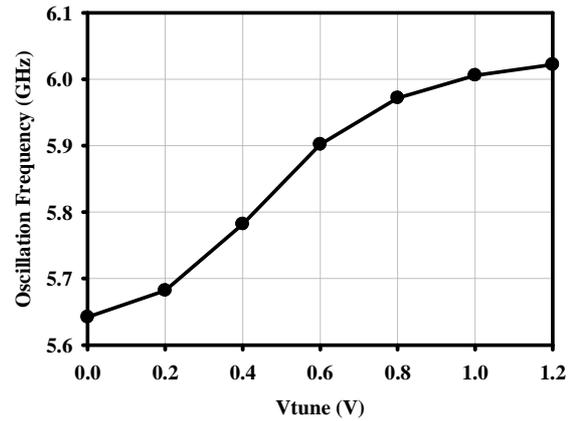


Fig. 6(b). Measured free-running frequency tuning range of the proposed divide-by-3 ILFD circuit. $V_{DD} = 0.5$ V, and $V_{inj} = 0.5$ V.

tune the capacitance of varactors and the oscillation frequency. The injection MOSFETs (M_1, M_2) with dc gate bias V_{inj} are used to couple the injection signal to the LC resonator.

In Fig. 5, the ILFD circuit is a double cross-coupled VCO with two injection MOSFETs, a pair of varactors C_{var} is used for frequency tuning, and it forms the resonator with the inductor L_0 . The voltage V_{tune} is used to tune the capacitance of varactors and the oscillation frequency. The injection MOSFETs (M_3, M_4) with dc gate bias V_{inj} are used to couple the injection signal to the LC resonator. The p-type transistors (M_1, M_2) and the n-type transistors (M_5, M_6) are used to generate the negative resistance to compensate for the tank loss.

3 Measurement and Discussion

The proposed circuit shown in Fig. 4 has been implemented in the retrograde twin-well TSMC 90nm 1P9M CMOS technology and the chip photo of the ILFD is shown in Fig. 6(a), where one center-tapped inductor and one transformer are shown on the left and right hand sides respectively. The die area of the chip with is $0.601 \times 0.858 \text{ mm}^2$. The measured tuning range is shown in Fig. 6(b). The tuning range of the ILFD is from 5.642 to 6.022 GHz at $V_{DD} = 0.5$ V. As the gate voltage of the varactors increases, the varactor's capacitance decreases, therefore the

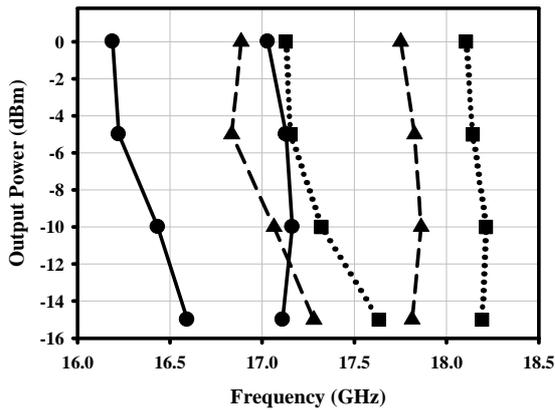


Fig. 6(c). Measured input sensitivity of the ILFD with 3 division ratio. $V_{DD} = 0.5$ V, $V_{inj} = 0.5$ V and $V_{tune} = 0.0, 0.5$ and 1.0 V from the left to the right.

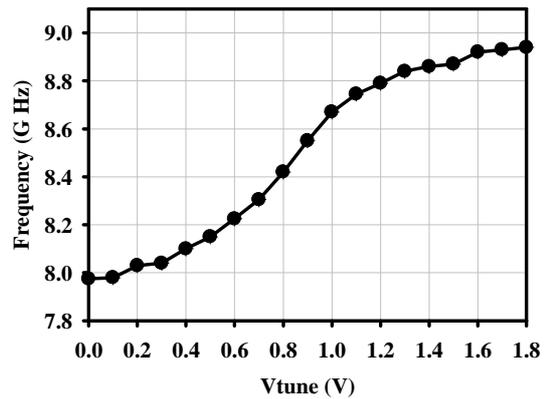


Fig. 7(a). Measured tuning range by varying V_{tune} of varactor. $V_{DD} = 1.8$ V.

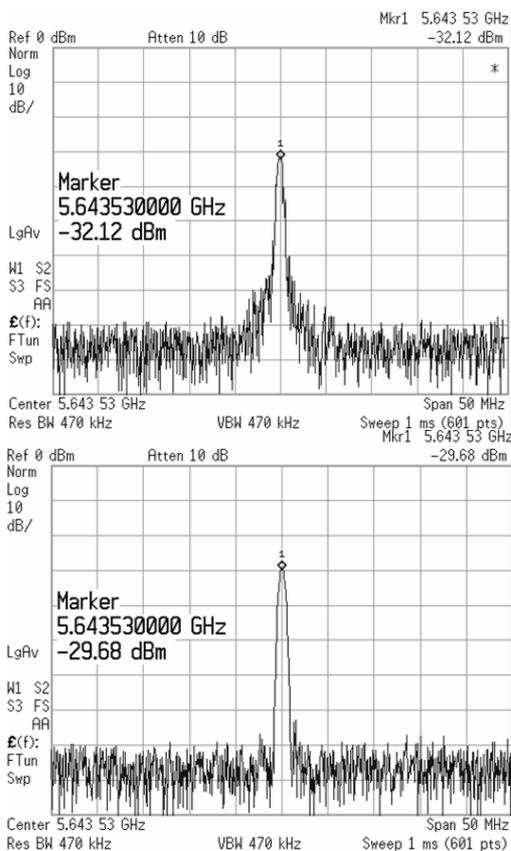


Fig. 6(d). Measured free running (top plot) and locked (bottom plot) spectra of the ILFD in the divide-by-3 mode. $V_{DD} = 0.5$ V, $V_{inj} = 0.5$ V, $f_{inj} = 16.93$ GHz.

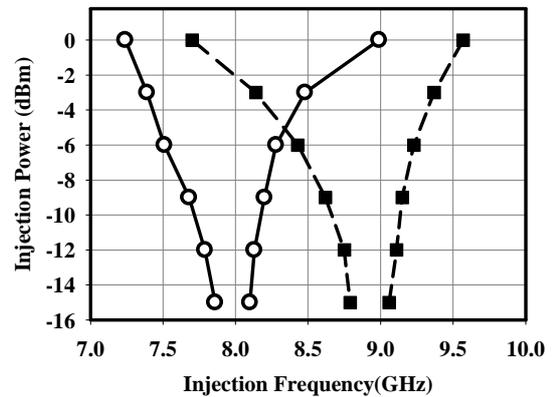


Fig. 7(b). The locking range of ILO. $V_{DD} = 1.8$ V, $V_{inj} = 1.25$ V, $V_{tune} = 0$ V and 1.8 V.

Tab.1 Comparison of ÷3 injection-locked frequency dividers

Ref.	Tech. (μm)	P_{in} (dBm)	V_{DD} (V)	P_{diss} (mW)	Operation Range (GHz)
[2]	0.18	4	1.8	4.59	16.7 ~ 17.7
[3]	0.35	10	1.5	15.15	6.9 ~ 8.4
[4]	0.18	0	1.8	4.97	15.04 ~ 17.12
This	0.18	0	1.8	5.4	25.5 ~ 30.3
This	0.09	0	0.5	2.63	16.19 ~ 18.105

oscillation frequency increases. Figure 6(c) shows the measured relationship between input sensitivity and operating frequency of the ÷3 ILFD under the condition of incident power $P_{in} = 0$ dBm, $V_{tune} = 0.0 \sim 1.0$ V and $V_{DD} = 0.5$ V, with a total operation locking range is 1.91 GHz, from 16.19 to 18.105 GHz. Figure 6(d) shows the measured output spectra of the divider before and after the locked conditions in the ÷3 mode. The locked output spectra show a lower phase noise. The ILFD can track the low-phase-noise of injection source.

The LC tank ILFD shown in Fig. 5 have been designed and fabricated in the TSMC 0.18 μm CMOS technology. Figure 7(a) shows the measured tuning curve of the first-harmonic ILO by varying the varactor's tuning voltage at $V_{inj} = 1.25$ V. The free-running tuning range is from 7.97 GHz to 8.94 GHz. The locking range is affected by the dc bias V_{inj} of M3 and M4. An optimum V_{inj} of 1.25 V is obtained for maximum locking range under a fixed injection power. Figure 7(b) shows the operation frequency and locking range dependence on input power for the first-harmonic injection-locked oscillator biased at $V_{DD} = 1.8$ V and $V_{inj} = 1.25$ V while varying V_{tune} . An external injected signal power of 0 dBm provides a total locking range of 7.24 to 9.57 GHz. We simulated the operation frequency

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